Subject Description Form

Subject Code	EIE3100 (for BEng in EIE)		
Subject Title	Analogue Circuit Fundamentals		
Credit Value	3		
Level	3		
Pre-requisite	EIE2100 Basic Circuit Analysis EIE2102 Basic Electronics		
Co-requisite/ Exclusion	Nil		
Objectives	This is the main foundation subject introducing the working principles and constructions of analog electronic circuits. The specific aim is to familiarize students with the design and operation of analog building blocks (e.g., mirrors, differential stages, output stages), practical operational amplifiers, frequency response of transistor amplifiers, feedback amplifiers and oscillators.		
Intended Subject Learning Outcomes	 Upon completion of the subject, students will be able to: <u>Category A: Professional/academic knowledge and skills</u> Understand the operations of transistor devices, e.g., BJT and MOSFET Analyze the small-signal characteristics of transistor amplifiers Design basic analog building blocks Understand the operations and limitations of operational amplifiers Analyze frequency responses and design feedback circuits and oscillators <u>Category B: Attributes for all-roundedness</u> Communicate effectively Think critically and creatively Assimilate new technological development in related field 		
Subject Synopsis/ Indicative Syllabus	 Syllabus: <u>Analog Building Blocks</u> Simple current mirrors; problem due to Early effect and non-ideality; Wilson and Widlar mirrors; use of mirrors as active loads. Differential amplifier (DA) stage; analysis using half-circuit models, common-mode and differential-mode gains; common-mode rejection ratio (CMRR). Output stages; class A, class B and class AB output stages; efficiency; harmonic distortions. <u>Operation Amplifier Design</u> Typical operational amplifier circuit: input differential stage, CE gain stage, and output stage; details of internal circuit design: active loading, level shift, current sourcing. Non-idealities: dc offset, input bias current (causing offset); finite input impedance, etc. Slew-rate limitation; gain-bandwidth product; stability design; concept of unity-gain feedback; phase margin; design of low-frequency pole and use of Miller effect for internal compensation. Feedback Circuits and Oscillators General feedback configuration; basic amplifier gain, loop gain and closed-loop (overall) gain. Effects of feedback on gain, frequency response, distortion, input and output impedances. Feedback circuit configurations: shunt-series, shunt-shunt, series- 		

	and compensa models. 3.4 Oscillation crit Colpitts, Hartle Laboratory Experiment Each student is required to 1. Title: Negative Feedb Objective: To design meet certain specifica 2. Title: Class AB Ampli Objective: To study th AB amplifier. 3. Title: Characteristics Objective: To study measure the character	tion methods; ar teria; amplitude y, Wien bridge, j s: to complete the f back Amplifier the feedback n ations. fier ne effects of bias of Operational <i>A</i> the internal ope eristics of the res	alysis of feedback circuits via two-port limiting and sustained oscillation; phase-shift and crystal oscillators. following three laboratory experiments: network for a given amplifier in order to sing on cross-over distortion of a Class Amplifier eration of an operation amplifier and sponses.
Teaching/ Learning Methodology	Teaching and Learning Method	Intended Subject Learning Outcome	Remarks
	Lectures	1, 2, 3, 4, 5	Fundamental principles and key concepts of the subject are delivered to students
	Tutorials	2, 3, 4, 5, 7, 8	Students will be able to clarify concepts and to have a deeper understanding of the lecture material; problems and application examples are given and discussed
	Laboratory sessions	3, 4, 5, 6, 7	Students in groups of 2-3 will conduct practical measurement and evaluate the performance of electronic circuits

Assessment Methods in Alignment with Intended Subject Learning Outcomes	Specific%AssessmentWeightingMethods/ TaskWeighting	Intended Subject Learning Outcomes to be Assessed (Please tick as appropriate)								
			1	2	3	4	5	6	7	8
	1. Continuous Assessment (total 50%)									
	Quizzes	10%	~	~	~	~	~			
	Laboratory sessions	20%				~	~	~	~	~
	• Test	20%	~	~	~	✓	~		~	
	2. Examination	50%	~	~	✓	~	✓		~	
	Total	100%		•	•	•	•	•		
	Explanation of the ap assessing the intend	propriateness o ed learning outc	f the omes	asse ::	ssm	ent	meth	ods	in	

Specific AssessmentRemarkMethods/Tasks		
Quizzes	Analytical and design problems are used to evaluate students' ability in applying concepts and skills learnt in the classroom.	
Test and examination	Mid-semester test is used students' ability to remember as well as their compreh materials;	I to measure the er facts and figures ension of subject
	Final exam is used to evaluate to think critically and creative up with an effective solution problem.	ate students' ability ely in order to come on for an existing
Laboratory sessions	Each group of students is re- written report;	quired to produce a
	Accuracy and the presentation be assessed;	on of the report will
	Assessment of the reports technical knowledge and abi effectively.	will focus on both lity to communicate
Class contact (time table	٠, ٩١, ٠	
Class contact (time-table	eu).	

Student Study Effort	Class contact (time-tabled):	
Expected	Lecture	24 Hours
	Tutorial/Laboratory/Practice Classes	15 hours
	Other student study effort:	
	 Lecture: preview/review of notes; homework/assignment; preparation for test/quizzes/examination 	36 Hours
	 Tutorial/Laboratory/Practice Classes: preview of materials, revision and/or reports writing 	30 Hours
	Total student study effort:	105 Hours

Reading List and References	Textbooks:			
	 S. Sedra and K.C. Smith, <i>Microelectronic Circuits</i>, 8th edition, Oxford University Press, 2021. 			
	Reference Books:			
	 Paul R. Gray, Paul J. Hurst, and Stephen H. Lewis, Analysis and Design of Analog Integrated Circuits, 5th edition, New York: Wiley, 2009. 			
	 D.A. Neamen, <i>Microelectronics Circuit Analysis and Design</i>, 4th edition, New York: McGraw-Hill, 2010. 			
	 D.A. Jones and K. Martin, Analog Integrated Circuit Design, New York: Wiley, 1997. 			
Last Updated	August 2023			
Prepared by	Dr. K.H. Loo			